

Search Notes



Application/Control No.

10/054,863

Examiner

Jennifer T. Nguyen

Applicant(s)/Patent under Reexamination

ISHIZUKA ET AL.

Art Unit

2674

SEARCHED

Class	Subclass	Date	Examiner
345	60-63	2/16/06	JN
	66-69		
	72		
	37		
	211, 212		
315	169.1-		
	169.4		
713	300		
	310		
348	725		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
345	60-72 37	2/16/06	JN
	211, 212		
315	169.1- 169.4		
713/300, 310 348/725			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Fast search Claim interference	2/16/06	JN